

### Portable One

Audio Precision Quality in a Portable Test Set

**Unmatched Portable Performance** 

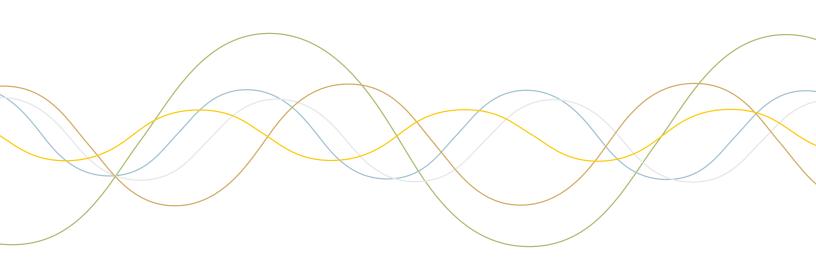


#### Available from:



Measurably better value

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# Portable One family of audio test instruments—at home on the bench or rugged in the field.

With thousands of units sold, you'll find the Portable One family of audio analyzers in operation around the world in maintenance, engineering and production facilities. Whether in broadcast and communications or bench and production use, Portable One offers a complete easy-to-use audio test set housed in a rugged case ready for almost anything. With twelve different measurement functions selectable with the push of a button, Portable One is comprehensive but user-friendly. But the popularity of Portable One is no less due to its outstanding performance specifications, even though it is priced just as affordable as lesser test sets.

### Analog Only or full Dual Domain—Analog and Digital

Portable One *Plus* Access includes comprehensive analog generation and measurement, two outputs and two inputs. Easy to set up sweep capability produces graphs of frequency response, distortion vs. frequency, even amplitude sweeps. Non-volatile storage of up to 30 tests allows easy one-button recall of your favorite test setup. Connect Portable One to a compatible printer to produce reports including high resolution graphs. If your needs include digital domain audio and digital interface measurements, **Portable One Dual Domain** adds digital audio capability to the comprehensive analog capabilities of the Portable One family.

#### Analog+Digital+AES/EBU/IEC:

Portable One Dual Domain® is a comprehensive audio test set for both analog and digital audio, as well as for generation and measurement of AES/EBU/IEC digital characteristics such as jitter. Like our System Two Cascade family, Portable One Dual Domain features true Dual Domain architecture. Digital signals are generated and measured purely in the digital domain, resulting in extremely low distortion and noise residuals necessary for making useful digital audio measurements.

### **Unparalleled Precision**

#### **Low Distortion**

Analog System THD+N 20kHz BW **-92dB**Digital Distortion THD+N ≤**-140dB High Analog Bandwidth** 

Signal Generation to 120kHz

**Low Noise** 

22-22kHz **< -114dBu** 

A-weighted < -118dBu

**Wide Input Voltage Range** 

Input Range 80mv—250V in 10dB steps

Flat Response

20-20kHz typically ±0.05dB

Low Crosstalk

Input < -120dB

Output < -110dB



# olutions

#### Performance, Measurement Power, and Ease-of-Use

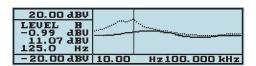
#### Easy to Use:

Measurement functions are simply selected from the front panel. Just press



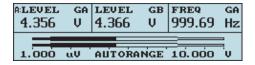
a button and make the measurement.
Selection of analog and digital inputs is clearly indicated on the front panel with LED legends.
Portable One Dual Domain makes

graphs of swept measurements in real time on the high contrast back-lit LCD display, including both Frequency and Amplitude sweeps. Hard copy high-resolution graphs, compact



screen-sized graphs or tabular data listings are made from Portable One Dual Domain to laser, ink jet or dot matrix printers at the touch of a button.

Bargraphs can display measurements ranging from AC mains power line



distortion to digital interface error rate ... and nearly everything in between. Separate buttons and knobs provide independent control of frequency and amplitude. The buttons provide large and

medium steps (decade and 1/3 octave steps for frequency, 10 dB and 1 dB for amplitude), with knobs for finer



resolution. When not otherwise used, the setting knobs and buttons also provide a convenient human interface for scrolling display cursors and for entry of other settings and data.

#### Stereo:

Portable One Dual Domain is a true two channel instrument. Both analog and digital level functions measure both



inputs simultaneously. Phase and level ratio measurements are also available.

### Full Range of Analog & Digital Testing Facilities:

Portable One Dual Domain provides complete and parallel measurement capabilities for both analog and digital audio signals. Measurements common to both domains include: Amplitude, Noise, Level (2 channels simultaneously), Frequency, Phase, THD+N, SMPTE/DIN, IMD, Crosstalk and Level Ratio. Standard A-weighting, CCIR 468, and LP/HP filters are included in both domains. RMS and quasi-peak (CCIR 468) detectors are available in both domains.

#### **Analog Performance:**

The low distortion transformer-coupled analog generator supplies a full 30.6 dBu (+30 dBm into 600 ohms) at selectable (40,150,600 $\Omega$ ) source impedances. Extremely low analyzer noise and residual distortion support measurement of high performance digital devices.

#### **Analog Convenience Functions:**

In addition to the above measurements, the analog *GEN LOAD* function measures the input resistance of your device at any frequency you choose and makes swept impedance measurements (including loudspeakers).

AC MAINS CHECK measures the voltage, frequency and distortion of the power line without hazardous direct connections. BARGRAPH display in AC MAINS CHECK function provides a visible history of maximum and minimum mains voltage excursions.

AAC MAINS 117.0 V	тно+n 4.8	×	FREQ 59.987	Hz
A:GEN:SINE	1.000	V	1.000	$\mathbf{kHz}$
SELF TEST				

The dBg unit (dB referred to the present analog generator amplitude) is useful for compression threshold measurements or rapid response sweeps at several different absolute levels, as well as for input to output gain/loss measurements. 600 ohm Analog Input Terminations are individually switchable for each channel of the analog analyzer.

# Comprehensive Analog and Digital Functions

#### **Digital Performance:**

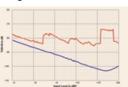
Portable One Dual Domain uses a true DSP-implemented analyzer for digital measurements, which results in -130 dB residual THD+N, 0.01 dB flatness, and -140 dBFS residual noise. Other mixed-signal test sets in the same price



range have no digital analyzer, but use a D/A converter and an analog analyzer. These architectures "bottom out" at -70 to -84 dB residual THD+N (12-14 bit effective performance), and 0.1 dB flatness. With today's best A/D converters measuring -104 to -108 dB

THD+N, their real performance is invisible to these mixed signal analyzers ... buried under the analyzer's noise and

distortion floor.



Competitive analyzer lacking DSP analyzer produces false THD+N readings (red trace) from a popular A/D converter. Both Portable One Dual Domain and System Two Dual Domain graph the true performance of the converter (from 5 dB to 28 dB lower), as represented by the trace in blue

# Separate & Independent Analog & Digital Generators:

Often necessary for dual domain testing. You may, for example, drive the inputs of an A/D converter with the low-distortion analog sine while simultaneously driving the converter's digital reference (house sync) input with the digital generator. Then, add jitter or vary the sample rate to see the

effect on THD+N, IMD, or noise.

Competitive units can drive only one domain at a time or use their analog generator to create the digital jitter, and thus can't make this measurement at all.

#### Separate Digital Inputs & Outputs:



Three I/O formats: XLR, BNC, and optical (Toslink®). All are completely separate from the analog audio XLR connectors, permitting both digital and analog generators to operate simultaneously. No cable changes required to go from A/D to D/A to D/D to A/A testing of a digital tape machine, for example.

#### **Digital & Analog Monitors:**

Listen to all measurements in the digital

and analog domains over the internal loudspeaker or a pair of



headphones. In analog domain, monitor signals or distortion. In digital domain, the incoming signal, distortion, or jitter can all be monitored.

#### Jitter Meter:

Portable One Dual Domain includes jitter measurement in nanoseconds or Unit

	xlr loz i 4.99 Vpp	J FREQ 1 400.46 Hz
0:GEN:SINE	1.0000 F5	997.00 H <sub>2</sub>
UN-WTD	HP: 50 Hz	RMS

Intervals and with a choice of 50Hz or 700 Hz high pass filters.

#### Other Interface Signal Measurements:

Portable One Dual Domain measures key digital I/O interface parameters in addition to jitter, including sample rate, AES signal voltage, frame delay through the device

	XLR LoZ G	
48000.0 Hz	2.98 Vpp	24.30 ns
D:GEN:SINE	1.0000 F%	$1.0000  \mathrm{kHz}$
REF: STAT	INP:24bit	OUT BLOCK

under test, and delay of the input signal relative to a house sync reference (frame or block).

#### Flexible Interface Impairment Simulation:

Flexible digital interface testing is vital for troubleshooting and verifying performance of digital audio at the systems level.

Portable One Dual Domain allows simulation of real world transmission and interface problems.



Vary the digital output signal to test the acceptance range of your digital devices. Set sample rate anywhere from 28.8 to 52.8 kHz, not just at the three standard frequencies. Inject jitter amplitude from zero to 2.5 UI (415 nanoseconds at 48 kHz) in 0.01 UI (1.6 ns) steps or zero to 25.5 UI (4150 ns) in 0.1 UI (16 ns) steps.

# challenges

Injected jitter frequency can be set from 10 Hz to 38.8 kHz, not just to a fixed frequency. Adjust output signal amplitude continuously from zero to 5.12 Volts in 5 mV increments, not just at a few steps. Only Portable One Dual Domain provides this flexibility in a Portable analyzer.

#### **Independent Interface I/O Word Widths:**

Word width of digital input & output are independently set from 12 to 24 bits.

Output width is set to match the device under test to assure proper dither. Input

48000.0 Hz		DELAY 260.72 UI
D:CEM:SINE	-60.00 AB%	1.0001 kHs
ref: Meas	INP:24bit	OUT BLOCK

width must be set to exclude signal in the AUX bits or other low-level bit activity meaningless to the desired measurement.

#### **Independent Input & Output Sample Rates:**

Lets you test sample rate converters.

Measurement of the incoming embedded audio signal can be referred to the incoming sample rate, status byte indication of rate, or the outgoing generator rate.

DSEND: CONS	EMPH: NONE	5R:32 kHz
PINP: CONS	EMPH: NONE	SR: 32kHz
COPY: NO		NO ERRORS
COPY: NO		VALID

## Data ✓ Error Testing Capability for Digital Audio Signals:

Stimulate the test device with random data and display current or totaled error measurements on both channels. The signal and analysis techniques are compatible with the BITTEST feature of our System products, so you can test a transmission link

DERROR GA 1567587T	DATA GB B71CD2hex
ior	 10000000

end-to-end with a Portable One Dual Domain at one end and a System Two, System Two Cascade or Cascade Plus Dual Domain at the other.

#### **Other Digital Convenience Functions:**

Digital Status bytes are displayed and set in high-level English.

D:ERROR	GA O	ERROR		DATA 6FEA401	GA IEX
24	816		1111	ACTIVEE	I T

D:	ERROR	GA O	ERRO		рата 5AOD6	ga Ohex
	24	16		8 ## #	ACTUA	LBIT

Error flag displays for confidence, lock, coding, parity errors and the validity bit are included.

Additional active bit and actual bit displays on the panel help determine the word width of the incoming signal & detect stuck bits.

#### **Digital Dither:**

Portable One Dual Domain includes a full complement of dither selections—triangular and rectangular probability distribution functions; white or shaped spectrum.

Dither amplitude is automatically set to the proper value for the output word width and the selected probability function.

#### Sample & Frame Sync:

Synchronize Portable One Dual Domain sample and frame sync to the digital reference (house sync) input.

#### Digital Pass Mode:

Sends the input digital audio content to the output while modifying status bytes, validity bit, etc. Portable One Dual Domain can thus be used as a problem-solver between incompatible equipment.

#### **Signal Monitoring Outputs:**

A digital signal appropriate for synching an external oscilloscope may be derived from the input sample rate, output sample rate, input block rate, output block rate, digital audio waveform, jitter signal, or the detected interface errors. A buffered version of the balanced AES/EBU signal from the XLR input is also available, which coupled with the high input impedance of the XLR in bridging mode allows non-intrusive digital line measurements with conventional ground referenced oscilloscopes.

#### **SAVE & RECALL TESTS:**

Save 30 instrument setups, including results data, time-stamped from the internal clock calendar. Use for repeatable, easy bench and production testing or when in the field, for storing test data to be printed or analyzed later. Each saved test



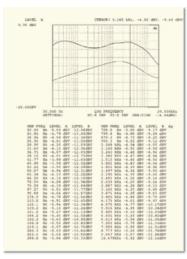
SAVE	CANCEL	SCROLL UP
15 A:THD+	N /D:AMPL	971017 00:22
16 XTALK	Data	971017 00:22
17 empty		
18	/A:FREQ	951112 17:50
19 GRAPH	A:FREQ	951112 17:50
RECALL	PAGE	SCROLL DN
RECHLL	PHGE	SCROLL DI

entire instrument, a default description or your own title for the test, the date and time, and the last test result data.

#### **Print Graphs and Test Results:**

includes all settings for the

Portable One Dual Domain prints graphs, panel setups and measured data either to laser (PCL compatible), inkjet or dot matrix (PCL or IBM Graphics mode) printers. Front panel keys select two sizes





of graph output (including cursor data), tabular sweep data, bargraphs and front panels for printing.

For a quick print, a compact graph provides a direct replication of the LCD screen. A larger graph printout covering approximately half a page (360x280 pixels with grid lines) allows finer detail to be shown. Both graphs show key instrument setup parameters as well. Tabular data values for all swept points may be printed in order to preserve exact reading values.

The bargraph displays, with their useful minimum/maximum indicators print just as they are seen on the display, as do any desired instrument panels. Various printouts may be combined on one page, to include graphs, bargraphs and numeric data.

#### INTERNAL CLOCK/CALENDAR:

An internal clock/calendar automatically stamps the time and date on setups and data as they are saved.

PRINTER PCL GRAPH	FREQ STEP 1.0000 kHz
	AMPL STEP 100.0 mV

You can view or set the clock/calendar from the Setup panel.

#### **GPIB Control:**

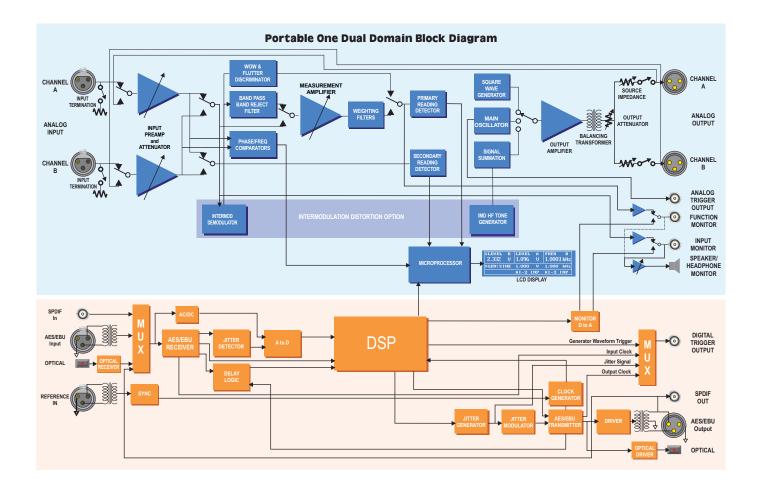
An IFFF-488 Interface is built in to allow control of the instrument in an automatic test environment. National Instruments LabWindows/CVI and LabVIEW drivers are available. A LabWindows/CVI soft front panel program is provided with a Windows user interface for real-time instrument control through the GPIB interface. The LabVIEW driver is provided with a Getting Started VI and sample VIs.



Low Distortion Sine Wave	
requency Range	10 Hz to 120 kHz
requency Accuracy	±0.5%
Amplitude Range	
Balanced Unhalanced	(20 Hz to 30 kHz) <0.25 mV to 26.25 Vrms [+30.6 dBu <0.25 mV to 12.50 Vrms [+24.6 dBu
Unbalanced Implitude Accuracy	±0.2dB [±2.3%] at 1 kHz
Amplitude Resolution	0.01 dB
latness (1 kHz ref)	
10 Hz-20 kHz	±0.05 dB
Residual THD+N 25 Hz-20 kHz	$\leq$ (0.0025% + 3 $\mu$ V), 80 kHz BW [-92 dB
Square Wave	=(01002310 + 3 per)) 00 1012 511   32 03
requency Range	20 Hz-30 kHz
Amplitude Range	LO TIZ-30 KIIZ
Balanced	0.25 mVpp to 34.4 Vpp 0.25 mVpp to 17.2 Vpp
Unbalanced	0.25 mVpp to 17.2 Vpp
Amplitude Accuracy	±0.3 dB [±3.5 %] at 400 Hz
Rise/fall time SMPTE (or DIN) Test Signals w	Typically 2.5 - 3.0 μsec
F Tone	
HF Tone Range	50, 60, 70, or 250; all ±1.0% 7 kHz or 8 kHz (±1%)
Mix Ratio	4:1 (LF:HF)
Residual IMD	0.0015% [-96.5 dB], 60+7 kHz or
	250+8 kHz
OUTPUT CHARACTERISTICS	
Source Configuration	Selectable balanced or unbalanced
Source Impedances Balanced	$40\Omega$ ( $\pm 2\Omega$ ), $150\Omega$ ( $\pm 2\Omega$ ), or $600\Omega$
Datanecu	(±2Ω) '
Unbalanced	40Ω (±2Ω)
Output Current Limit	75 mA peak
Max Output Power Balanced	+30.1 dBm into 600* (Rs = 40*)
Unbalanced	+30.1 dBm into 600* (Rs = 40*) +24.4 dBm into 600* (Rs = 20*)
Output Related Crosstalk	$\leq$ -110 dB or 10 $\mu$ V, whichever is
10Hz-20kHz)	greater
ANALOG ANALYZER	
ANALOG INPUT CHARACTERIST	TICS
input Ranges	80 mV to 250 V in 10 dB steps
Maximum Rated Input	350Vpk, 140Vrms (dc to 20kHz);
	overload protected
input Impedance	Nominally 100 kQ // 150, 2005E
Balanced (each side) Unbalanced	Nominally 100 kΩ // 150-200pF Nominally 100 kΩ // 150-200pF
Terminations	Selectable 600 $\Omega$ ±1%
CMRR 80mV-2.5V range	≥70 dB, 50 Hz-20 kHz
Input Related Crosstalk	$\leq$ -120 dB or 1 $\mu$ V, whichever is greate
10 Hz-20 kHz Nidoband Amplitudo (Noico E	unction
Wideband Amplitude/Noise Fo	
Measurement Range	$<1 \mu V-140 \text{ Vrms} [-118 \text{ dBu to} + 45 \text{ dBu} \\ \pm 2.0\% [*0.2 \text{ dB}] \text{ unweighted}$
Accuracy (1 kHz) Flatness (1 kHz ref)	±0.05 dB (20 Hz-20 kHz)
Bandwidth Limiting Filters	
LF -3 dB	<10 Hz; 400 Hz ±5% (3-pole)
HF -3 dB	22 kHz; 30 kHz; 80 kHz (3-pole), or 300 kHz
Weighting Filters	ANSI-IEC "A"; CCIR-QPK; CCIR-ARM;
	CCIR-RMS
Optional Filters	Up to 2 (Aux 1 and Aux 2)
Detection	RMS ( <i>i</i> =60 msec); AVG; QPK (CCIR
500000000000000000000000000000000000000	Rec 468)
Residual Noise	Rec 468)
Residual Noise 22 Hz-22 kHz BW	
Residual Noise 22 Hz-22 kHz BW A-weighted	
Residual Noise 22 Hz-22 kHz BW A-weighted CCIR-QPK	≤1.5 μV [-114 dBu] ≤1.0 μV [-118 dBu] ≤5.0 μV [-104 dBu]
Residual Noise 22 Hz-22 kHz BW A-weighted CCIR-QPK Frequency Meter Related (bot	≤1.5 $\mu$ V [-114 dBu] ≤1.0 $\mu$ V [-118 dBu] ≤5.0 $\mu$ V [-104 dBu] th channels)
Residual Noise 22 Hz-22 kHz BW A-weighted CCIR-QPK Fr <b>equency Meter Related (bot</b> Measurement Range	≤1.5 $\mu$ V [-114 dBu] ≤1.0 $\mu$ V [-118 dBu] ≤5.0 $\mu$ V [-104 dBu] th channels)
Residual Noise 22 Hz-22 kHz BW A-weighted CCIR-QPK Frequency Meter Related (bot Measurement Range Accuracy	≤1.5 $\mu$ V [-114 dBu] ≤1.0 $\mu$ V [-118 dBu] ≤5.0 $\mu$ V [-104 dBu] th channels)
Residual Noise 22 Hz-22 kHz BW A-weighted CCIR-QPK Frequency Meter Related (bot Measurement Range Accuracy Resolution	$\leq 1.5 \ \mu \text{V} \ [-114 \ \text{dBu}]$ $\leq 1.0 \ \mu \text{V} \ [-118 \ \text{dBu}]$ $\leq 5.0 \ \mu \text{V} \ [-104 \ \text{dBu}]$ th channels) $10 \ \text{Hz} = 200 \ \text{Hz}$ $\pm 0.01\% \ [\pm 100 \ \text{PPM}]$
Residual Noise 22 Hz-22 kHz BW A-weighted CCIR-QPK Trequency Meter Related (bot Measurement Range Accuracy Resolution Phase Measurement Related	$\leq 1.5 \ \mu \text{V} \ [-114 \ \text{dBu}]$ $\leq 1.0 \ \mu \text{V} \ [-118 \ \text{dBu}]$ $\leq 5.0 \ \mu \text{V} \ [-104 \ \text{dBu}]$ th channels) $10 \ \text{Hz} = 200 \ \text{Hz}$ $\pm 0.01\% \ [\pm 100 \ \text{PPM}]$
Residual Noise  22 Hz-22 kHz BW A-weighted CCIR-OPK Frequency Meter Related (bot Measurement Range Accuracy Resolution Phase Measurement Related Measurement Range	≤1.5 $\mu$ V [-114 dBu] ≤1.0 $\mu$ V [-118 dBu] ≤5.0 $\mu$ V [-104 dBu] th channels) 10 Hz-200 kHz ±0.01% [±100 PPM] 5 digits ±180, +90/-270, or -90/+270 deg ±2.0 deg
Residual Noise 22 Hz-22 kHz BW A-weighted CCIR-QPK Frequency Meter Related (bot Measurement Range Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz	≤1.5 $\mu$ V [-114 dBu] ≤1.0 $\mu$ V [-118 dBu] ≤5.0 $\mu$ V [-104 dBu] th channels) 10 Hz-200 kHz ±0.01% [±100 PPM] 5 digits
Residual Noise  22 Hz-22 kHz BW A-weighted CCIR-QPK  Frequency Meter Related (bot Measurement Range Accuracy Resolution  Measurement Related Measurement Ranges Accuracy Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution	≤1.5 $\mu$ V [-114 dBu] ≤1.0 $\mu$ V [-118 dBu] ≤5.0 $\mu$ V [-104 dBu] th channels) 10 Hz-200 kHz ±0.01% [±100 PPM] 5 digits ±180, +90/-270, or -90/+270 deg ±2.0 deg 0.1 deq
Residual Noise  22 Hz-22 kHz BW A-weighted CCIR-QPK  Frequency Meter Related (bot Measurement Range Accuracy Resolution  Measurement Ranges Accuracy 20 Hz-20 kHz Resolution  Level Meter Related (both cha	≤1.5 µV [-114 dBu] ≤1.0 µV [-118 dBu] ≤5.0 µV [-104 dBu] ★ channels)  10 Hz-200 kHz  ±0.01% [±100 PPM]  5 digits  ±180, +90/-270, or -90/+270 deg ±2.0 deg 0.1 deq minels)  10 mV-140 V for specified accuracy
Residual Noise  22 Hz-22 kHz BW A-weighted CCIR-QPK  Frequency Meter Related (bot Measurement Range Accuracy Resolution  Measurement Ranges Accuracy 20 Hz-20 kHz Resolution  Level Meter Related (both cha	≤1.5 µV [-114 dBu] ≤1.0 µV [-118 dBu] ≤5.0 µV [-104 dBu] th channels) 10 Hz-200 kHz ±0.01% [±100 PPM] 5 digits ±180, +90/-270, or -90/+270 deg ±2.0 deg 0.1 deq 31nnels) 10 mV-140 V for specified accuracy and flatness, useable to -100 µV
Residual Noise 22 Hz-22 kHz BW A-weighted CCIR-OPK Frequency Meter Related (bot Measurement Range Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both cha	≤1.5 µV [-114 dBu] ≤1.0 µV [-118 dBu] ≤5.0 µV [-104 dBu] th channels) th channels th channels ±0.01% [±100 PPM] 5 digits ±180, +90/-270, or -90/+270 deg ±2.0 deg 0.1 deq table to 400 µV 10 mV-140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu]
Residual Noise  22 Hz-22 kHz BW A-weighted CCIR-OPK Frequency Meter Related (bot Measurement Range Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Resolution Accuracy 1 Hz Resolution Resolution Resolution Resolution Resolution Resolution Resolution Resolution Resultion Result	≤1.5 $\mu$ V [-114 dBu] ≤1.0 $\mu$ V [-118 dBu] ≤5.0 $\mu$ V [-118 dBu] ≤5.0 $\mu$ V [-104 dBu] th channels) 10 Hz-200 kHz ±0.01% [±100 PPM] 5 digits ±180, +90/-270, or -90/+270 deg ±2.0 deg 0.1 deq mnels) 10 mV-140 V for specified accuracy and flatness, useable to <100 $\mu$ V [-38 dBu to + 45 dBu] ±0.1 dB + 100 $\mu$ V
Residual Noise  22 Hz-22 kHz BW A-weighted CCIR-QPK  Frequency Meter Related (bot Measurement Range Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both cha Measurement Range	≤1.5 $\mu$ V [-114 dBu] ≤1.0 $\mu$ V [-118 dBu] ≤1.0 $\mu$ V [-118 dBu] ≤5.0 $\mu$ V [-104 dBu] th channels) 10 Hz-200 kHz ±0.01% [±100 PPM] 5 digits ±180, +90/-270, or -90/+270 deg ±2.0 deg 0.1 deg mnels) 10 mV-140 V for specified accuracy and flatness, useable to <100 $\mu$ V [-38 dBu to + 45 dBu] ±0.1 dB + 100 $\mu$ V (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz
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Residual Noise  22 Hz-22 kHz BW  A-weighted  CCIR-OPK  Frequency Meter Related (bot Measurement Range Accuracy Resolution  Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution  Level Meter Related (both cha Measurement Range  Accuracy (1 kHz)  Elatness (1 kHz ref)  Bandpass Amplitude Function  Guning Range (f <sub>0</sub> )	≤1.5 $\mu$ V [-114 dBu] ≤1.0 $\mu$ V [-118 dBu] ≤1.0 $\mu$ V [-104 dBu] ★1.0 $\mu$ V [-104 dBu] th channels) 10 Hz-200 kHz ±0.01% [±100 PPM] 5 digits ±180, +90/-270, or -90/+270 deg ±2.0 deg 0.1 deq 3nnels) 10 mV-140 V for specified accuracy and flatness, useable to <100 $\mu$ V [-38 dBu to + 45 dBu] ±0.1 dB + 100 $\mu$ V (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz)
Residual Noise  22 Hz-22 kHz BW A-weighted CCIR-OPK Frequency Meter Related (bot Measurement Range Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Accuracy 21 Hz-20 kHz Resolution R	≤1.5 $\mu$ V [-114 dBu] ≤1.0 $\mu$ V [-118 dBu] ≤1.0 $\mu$ V [-118 dBu] ≤5.0 $\mu$ V [-104 dBu] th channels) 10 Hz-200 kHz ±0.01% [±100 PPM] 5 digits ±180, +90/-270, or -90/+270 deg ±2.0 deg 0.1 deq annels) 10 mV-140 V for specified accuracy and flatness, useable to <100 $\mu$ V [-38 dBu to + 45 dBu] ±0.1 dB + 100 $\mu$ V (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz
Residual Noise  22 Hz-22 kHz BW  A-weighted  CCIR-OPK  Frequency Meter Related (bot Measurement Range Accuracy Resolution  Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution  Level Meter Related (both cha Measurement Range  Accuracy (1 kHz)  Flatness (1 kHz ref)  Bandpass Amplitude Function  Guning Range (f <sub>n</sub> )  Bandpass Response  Accuracy (at f.)	≤1.5 µV [-114 dBu] ≤1.0 µV [-118 dBu] ≤5.0 µV [-104 dBu] h channels) 10 Hz-200 kHz ±0.01% [±100 PPM] 5 digits ±180, +90/-270, or -90/+270 deg ±2.0 deg 0.1 deg mnels) 10 mV-140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu] ±0.1 dB + 100 µV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz) 20 Hz to 120 kHz Q=5 (2-pole)
Residual Noise  22 Hz-22 kHz BW A-weighted CCIR-OPK  Frequency Meter Related (bot Measurement Range Accuracy Resolution  Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution  Level Meter Related (both cha Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function funing Range (f <sub>0</sub> ) Bandpass Response Accuracy (at f <sub>1</sub> )  IHD+N / SINAD Function	≤1.5 $\mu$ V [-114 dBu] ≤1.0 $\mu$ V [-118 dBu] ≤1.0 $\mu$ V [-118 dBu] ≤5.0 $\mu$ V [-104 dBu] th channels) 10 Hz-200 kHz ±0.01% [±100 PPM] 5 digits ±180, +90/-270, or -90/+270 deg ±2.0 deg 0.1 deg annels) 10 mV-140 V for specified accuracy and flatness, useable to <100 $\mu$ V [-38 dBu to + 45 dBu] ±0.1 dB + 100 $\mu$ V (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz 20 Hz to 120 kHz =0-5 (2-pole) ±0.3 dB, 20 Hz-120 kHz
Residual Noise 22 Hz-22 kHz BW A-weighted CCIR-QPK Frequency Meter Related (bot Measurement Range Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both cha Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Funing Range (f <sub>0</sub> ) Bandpass Response Accuracy (at f.) FIHD+N / SINAD Function Fundamental Range	≤1.5 µV [-114 dBu] ≤1.0 µV [-118 dBu] ≤1.0 µV [-118 dBu] ≤5.0 µV [-104 dBu] ht channels)  10 Hz-200 kHz ±0.01% [±100 PPM] 5 digits  ±180, +90/-270, or -90/+270 deg ±2.0 deg 0.1 deq  annels)  10 mV-140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu] ±0.1 dB + 100 µV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz)  20 Hz to 120 kHz Q=5 (2-pole) ±0.3 dB, 20 Hz-120 kHz
Residual Noise  22 Hz-22 kHz BW  A-weighted  CCIR-QPK  Frequency Meter Related (bot  Measurement Range  Accuracy  Resolution  Phase Measurement Related  Measurement Ranges  Accuracy 20 Hz-20 kHz  Resolution  Level Meter Related (both cha  Measurement Range  Accuracy (1 kHz)  Flatness (1 kHz ref)  Bandpass Amplitude Function  Tuning Range (f <sub>0</sub> )  Bandpass Response  Accuracy (at f <sub>.</sub> )  ThD+N / SINAD Function  Tundamental Range  Measurement Range	≤1.5 $\mu$ V [-114 dBu] ≤1.0 $\mu$ V [-118 dBu] ≤1.0 $\mu$ V [-118 dBu] ≤5.0 $\mu$ V [-104 dBu] th channels) 10 Hz-200 kHz ±0.01% [±100 PPM] 5 digits ±180, +90/-270, or -90/+270 deg ±2.0 deg 0.1 deg annels) 10 mV-140 V for specified accuracy and flatness, useable to <100 $\mu$ V [-38 dBu to + 45 dBu] ±0.1 dB + 100 $\mu$ V (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz 20 Hz to 120 kHz =0-5 (2-pole) ±0.3 dB, 20 Hz-120 kHz
Residual Noise 22 Hz-22 kHz BW A-weighted CCIR-QPK Frequency Meter Related (bot Measurement Range Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution  Level Meter Related (both charmed the control of	≤1.5 µV [-114 dBu] ≤1.0 µV [-118 dBu] ≤1.0 µV [-118 dBu] ≤5.0 µV [-104 dBu] h channels)  10 Hz-200 kHz ±0.01% [±100 PPM] 5 digits  ±180, +90/-270, or -90/+270 deg ±2.0 deg 0.1 deq annels) 10 mV-140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu] ±0.1 dB + 100 µV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz)  20 Hz to 120 kHz Q=5 (2-pole) ±0.3 dB, 20 Hz-120 kHz  10 Hz to 100 kHz, THD+N mode 001%-100% ±1 dB, 20 Hz-120 kHz harmonics
Residual Noise  22 Hz-22 kHz BW  A-weighted  CCIR-OPK  Frequency Meter Related (bot  Measurement Range  Accuracy  Resolution  Phase Measurement Related  Measurement Ranges  Accuracy 20 Hz-20 kHz  Resolution  Level Meter Related (both cha  Measurement Range  Accuracy (1 kHz)  Flatness (1 kHz ref)  Bandpass Amplitude Function  Funing Range (f <sub>0</sub> )  Bandpass Response  Accuracy (at f.)  FIHD+N / SINAD Function  Fundamental Range  Measurement Bandwidth  LF-3 dB	≤1.5 µV [-114 dBu] ≤1.0 µV [-118 dBu] ≤5.0 µV [-118 dBu] ≤5.0 µV [-104 dBu] h channels)  10 Hz-200 kHz ±0.01% [±100 PPM] 5 digits  ±180, +90/-270, or -90/+270 deg ±2.0 deg 0.1 deg mnels)  10 mV-140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu] ±0.1 dB + 100 µV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz)  20 Hz to 120 kHz 20 Hz to 120 kHz 10 Hz to 100 kHz, THD+N mode .001%-100% ±1 dB, 20 Hz-120 kHz harmonics <10 or 400 Hz
Residual Noise 22 Hz-22 kHz BW A-weighted CCIR-OPK Frequency Meter Related (bot Measurement Range Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both cha Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Guning Range (f <sub>0</sub> ) Bandpass Response Accuracy (at f <sub>1</sub> ) FIHD+N / SINAD Function Fundamental Range Measurement Range Measurement Range Measurement Range Measurement Range Measurement Bandwidth LF - 3 dB HF - 3 dB	≤1.5 µV [-114 dBu] ≤1.0 µV [-118 dBu] ≤1.0 µV [-118 dBu] ≤5.0 µV [-104 dBu] h channels)  10 Hz-200 kHz ±0.01% [±100 PPM] 5 digits  ±180, +90/-270, or -90/+270 deg ±2.0 deg 0.1 deq annels) 10 mV-140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu] ±0.1 dB + 100 µV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz)  20 Hz to 120 kHz Q=5 (2-pole) ±0.3 dB, 20 Hz-120 kHz  10 Hz to 100 kHz, THD+N mode 001%-100% ±1 dB, 20 Hz-120 kHz harmonics
Residual Noise  22 Hz-22 kHz BW  A-weighted CCIR-OPK  Frequency Meter Related (bot Measurement Range Accuracy Resolution  Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution  Acesolution	≤1.5 µV [-114 dBu] ≤1.0 µV [-118 dBu] ≤1.0 µV [-118 dBu] ≤5.0 µV [-104 dBu] h channels)  10 Hz-200 kHz ±0.01% [±100 PPM] 5 digits  ±180, +90/-270, or -90/+270 deg ±2.0 deg 0.1 deq annels) 10 mV-140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu] ±0.1 dB + 100 µV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz  20 Hz to 120 kHz =0-5 (2-pole) ±0.3 dB, 20 Hz-120 kHz  10 Hz to 100 kHz, THD+N mode .001%-100% ±1 dB, 20 Hz-120 kHz harmonics <10 or 400 Hz 22K, 30k, 80k, or 300 kHz ≤(0.0025% + 3.0 µV), 80 kHz BW
Residual Noise 22 Hz-22 kHz BW A-weighted CCUR-OPK Frequency Meter Related (both Measurement Range Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution R	\$\leq 1.5 \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \
Residual Noise 22 Hz-22 kHz BW A-weighted CCIR-OPK  Frequency Meter Related (both Reasurement Range CCURACOPK  Phase Measurement Related Reasurement Ranges CCURACOPK  Reasurement Ranges CCURACOPK  Reasurement Ranges CCURACOPK  Reasurement Range  Recouracy 20 Hz-20 kHz  Resolution  Revel Meter Related (both characopy Reasurement Range  Recouracy (1 kHz)  Randpass Amplitude Function  Runing Range (f <sub>n</sub> )  Randpass Response  Recuracy (at f,)  RHD+N / SINAD Function  Rundamental Range Reasurement Range Reasurement Range Reasurement Bandwidth  LF - 3 dB  HF - 3 dB  HF - 3 dB  Residual THD+N 25 Hz-20 kHz	≤1.5 µV [-114 dBu] ≤1.0 µV [-118 dBu] ≤1.0 µV [-118 dBu] ≤5.0 µV [-104 dBu] h channels)  10 Hz-200 KHz ±0.01% [±100 PPM] 5 digits  ±180, +90/-270, or -90/+270 deg ±2.0 deg 0.1 deq annels) 10 mV-140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu] ±0.1 dB + 100 µV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz  20 Hz to 120 kHz =0-5 (2-pole) ±0.3 dB, 20 Hz-120 kHz  10 Hz to 100 kHz, THD+N mode .001%-100% ±1 dB, 20 Hz-120 kHz harmonics <10 or 400 Hz 22K, 30k, 80k, or 300 kHz ≤(0.0025% + 3.0 µV), 80 kHz BW
Residual Noise 22 Hz-22 kHz BW A-weighted CCIR-OPK Frequency Meter Related (bot Aeasurement Range Accuracy Resolution Phase Measurement Related Aeasurement Ranges Accuracy 20 Hz-20 kHz Resolution Aeasurement Ranges Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Flatness (1 kHz ref) Bandpass Amplitude Function Flatness (1 kHz ref) Bandpass Response Accuracy (at f.) Flatness (1 kHz ref) Bandpass Response Accuracy (at f.) Flatness Amplitude Function Flatness	≤1.5 µV [-114 dBu] ≤1.0 µV [-118 dBu] ≤1.0 µV [-118 dBu] ≤5.0 µV [-104 dBu] h channels)  10 Hz-200 KHz ±0.01% [±100 PPM] 5 digits  ±180, +90/-270, or -90/+270 deg ±2.0 deg 0.1 deq annels) 10 mV-140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu] ±0.1 dB + 100 µV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz  20 Hz to 120 kHz =0-5 (2-pole) ±0.3 dB, 20 Hz-120 kHz  10 Hz to 100 kHz, THD+N mode .001%-100% ±1 dB, 20 Hz-120 kHz harmonics <10 or 400 Hz 22K, 30k, 80k, or 300 kHz ≤(0.0025% + 3.0 µV), 80 kHz BW

SMPTE (DIN) IMD Function wit	h option "P1-IMD"
Test Signal Compatibility	40-250 Hz and 3 kHz-20 kHz in 0:1 to 8:1 ratio
IMD Measured	Amplitude modulation products of the HF tone.
Measurement Range Accuracy	<0.0025%-20% ±1 dB per SMPTE RP-120-1983,
Residual IMD	DIN 45403 ≤0.0025% [-92 dB], 60 + 7 kHz or
	250 + 8 kHz
Wow & Flutter Function Test Signal Compatibility	2.80 kHz-3.35 kHz
Accuracy (4 Hz) Detection Modes	±(5% of reading + 0.002%) IEC/DIN; NAB; JIS
Residual W+F	≤0.005% Weighted; ≤0.01% Unweighted
DIGITAL SIGNAL GENERATO	_
DIGITAL OUTPUT CHARACTERIS	
Output Formats	AES/EBU (per AES3-1992); SPDIF-EIAJ; Optical
Sample Rates Sample Rate Accuracy	28.8 kHz-52.8 kHz AES/EBU ±0.002% [±20 PPM] lockable to
Word Width	external reference
Sine Wave	12 to 24 bits (even values)
Frequency Range	10 Hz to 47% of sample rate (22.56 kHz at 48 ks/s)
Frequency Resolution	Sample Rate ÷ 223 (typically 0.006 Hz at 48 ks/sec)
Flatness	±0.001 dB
Residual Distortion Square Wave	±0.00001% [-140 dB]
Frequency Range	10 Hz to 1/6 sample rate
Frequencies available	$f_s \div 4096$ to $f_s \div 6$ , in even integer divisors
Inner Tone Pange	h option "P1-IMD"  Choice of 7 kHz or 8 kHz
Upper Tone Range Lower Tone Range	Choice of 50 Hz, 60 Hz, 70 Hz, or 250 Hz
Amplitude Ratio Residual Distortion	4:1 (LF:HF) ≤0.00001% [-140 dB] at 4:1 ratio
Random Generator Waveform	
Waveform	Compatible with BITTEST used in System One
Dither (all waveforms)	<u> </u>
Probability Distribution	Triangular or rectangular; independent each channel
Spectral Distribution	Flat (white) or Shaped (+6 dB/oct, triangular only)
Amplitude	Automatically tracks word width or off
AES/EBU INTERFACE GENE Interface Signal	KATION
Amplitude Range Balanced (XLR)	0–5.12 Vpp, into $110\Omega$ in 5 mV steps
Unbalanced (BNC)	0–1.28 Vpp, into 75Ω in 1.25 mV steps
Channel Status Bits	English language decoded, Professional/Consumer
Validity Flag AES/EBU Impairments	Selectable, set or cleared
Induced Jitter	
Jitter Freq Range	Sinewave
Jitter Amplitude	10 Hz to 38.8 kHz 0-1.28 UI (pk), in steps of 0.005 UI
Jitter Amplitude	10 Hz to 38.8 kHz 0–1.28 UI (pk), in steps of 0.005 UI or better 1.3–12.75 UI, in steps of 0.05 UI or
Jitter Amplitude  Residual Jitter	10 Hz to 38.8 kHz 0-1.28 UI (pk), in steps of 0.005 UI or better 1.3-12.75 UI, in steps of 0.05 UI or better (total qenerator/analyzer) peak calibrated
Jitter Amplitude  Residual Jitter RMS response Peak response	10 Hz to 38.8 kHz 0-1.28 UI (pk), in steps of 0.005 UI or better 1.3-12.75 UI, in steps of 0.05 UI or better
Residual Jitter RMS response Peak response Spurious Jitter Products Jitter & Ref Delay Off	10 Hz to 38.8 kHz 0-1.28 UI (pk), in steps of 0.005 UI or better 1.3-12.75 UI, in steps of 0.05 UI or better (total generator/analyzer) peak calibrated ≤0.005 UI (700 Hz-30 kHz BW) ≤0.005 UI (700 Hz-30 kHz BW)
Residual Jitter RMS response Peak response Spurious Jitter Products Jitter & Ref Delay Off Jitter On	10 Hz to 38.8 kHz 0-1.28 UI (pk), in steps of 0.005 UI or better 1.3-12.75 UI, in steps of 0.05 UI or better (total generator/analyzer) peak calibrated ≤0.005 UI (700 Hz-30 kHz BW) ≤0.015 UI (700 Hz-30 kHz BW) ≤0.005 UI ≤-30 dB below jitter signal
Residual Jitter RMS response Peak response Spurious Jitter Products Jitter & Ref Delay Off Jitter On REFERENCE INPUT CHARACTER! Input Formats	10 Hz to 38.8 kHz 0-1.28 UI (pk), in steps of 0.005 UI or better 1.3-12.75 UI, in steps of 0.05 UI or better (total generator/analyzer) peak calibrated ≤0.005 UI (700 Hz-30 kHz BW) ≤0.015 UI (700 Hz-30 kHz BW) ≤3.005 UI (700 Hz-30 kHz BW)  ≤3.0005 UI ≤3.0005 UI STICS AES/EBU (per AES 3-1992)
Residual Jitter RMS response Peak response Spurious Jitter Products Jitter & Ref Delay Off Jitter On REFERENCE INPUT CHARACTER!	10 Hz to 38.8 kHz 0-1.28 UI (pk), in steps of 0.005 UI or better 1.3-12.75 UI, in steps of 0.05 UI or better (total generator/analyzer) peak calibrated ≤0.005 UI (700 Hz-30 kHz BW) ≤0.015 UI (700 Hz-30 kHz BW) ≤0.005 UI ≤-30 dB below jitter signal
Residual Jitter RMS response Peak response Spurious Jitter Products Jitter & Ref Delay Off Jitter On REFERENCE INPUT CHARACTER! Input Formats Input Sample Rates	10 Hz to 38.8 kHz 0-1.28 UI (pk), in steps of 0.005 UI or better 1.3-12.75 UI, in steps of 0.05 UI or better (total generator/analyzer) peak calibrated ≤0.005 UI (700 Hz-30 kHz BW) ≤0.005 UI (700 Hz-30 kHz BW) ≤0.005 UI ≤-30 dB below jitter signal  STICS AES/EBU (per AES 3-1992) 28.8 kHz-52.8 kHz AES/EBU
Residual Jitter RMS response Peak response Spurious Jitter Products Jitter & Ref Delay Off Jitter On REFERENCE INPUT CHARACTER! Input Formats Input Sample Rates Lock Range DIGITAL ANALYZER DIGITAL INPUT CHARACTERIST	10 Hz to 38.8 kHz 0-1.28 UI (pk), in steps of 0.005 UI or better 1.3-12.75 UI, in steps of 0.05 UI or better (total generator/analyzer) peak calibrated ≤0.005 UI (700 Hz-30 kHz BW) ≤0.0015 UI (700 Hz-30 kHz BW) ≤0.005 UI ≤-30 dB below jitter signal  STICS AES/EBU (per AES 3-1992) 28.8 kHz-52.8 kHz AES/EBU ±0.0025% [±25 PPM]
Residual Jitter RMS response Peak response Spurious Jitter Products Jitter & Ref Delay Off Jitter On REFERENCE INPUT CHARACTER! Input Formats Input Sample Rates Lock Range DIGITAL ANALYZER DIGITAL INPUT CHARACTERIST. Input Formats	10 Hz to 38.8 kHz 0-1.28 UI (pk), in steps of 0.005 UI or better 1.3-12.75 UI, in steps of 0.05 UI or better (total generator/analyzer) peak calibrated ≤0.005 UI (700 Hz-30 kHz BW) ≤0.015 UI (700 Hz-30 kHz BW) ≤-30 dB below jitter signal STICS AES/EBU (per AES 3-1992) 28.8 kHz-52.8 kHz AES/EBU ±0.0025% [±25 PPM]
Residual Jitter RMS response Peak response Spurious Jitter Products Jitter & Ref Delay Off Jitter On REFERENCE INPUT CHARACTER! Input Formats Input Sample Rates Lock Range DIGITAL ANALYZER DIGITAL INPUT CHARACTERIST. Input Formats Sample Rates With 96k Option	10 Hz to 38.8 kHz 0-1.28 UI (pk), in steps of 0.005 UI or better 1.3-12.75 UI, in steps of 0.05 UI or better (total generator/analyzer) peak calibrated ≤0.005 UI (700 Hz-30 kHz BW) ≤0.015 UI (700 Hz-30 kHz BW) ≤0.0005 UI ≤-30 dB below jitter signal STICS AES/EBU (per AES 3-1992) 28.8 kHz-52.8 kHz AES/EBU ±0.0025% [±25 PPM]  ICS AES/EBU (per AES 3-1992); SPDIF-EIAJ; Optical 28.8 kHz-52.8 kHz AES/EBU Add 57.6 kHz-105.6 kHz
Residual Jitter RMS response Peak response Spurious Jitter Products Jitter & Ref Delay Off Jitter On REFERENCE INPUT CHARACTER! Input Sample Rates Lock Range DIGITAL ANALYZER DIGITAL INPUT CHARACTERIST. Input Formats Input Formats Sample Rates With 96k Option Word Width	10 Hz to 38.8 kHz 0-1.28 UI (pk), in steps of 0.005 UI or better 1.3-12.75 UI, in steps of 0.05 UI or better (total generator/analyzer) peak calibrated ≤0.005 UI (700 Hz-30 kHz BW) ≤0.015 UI (700 Hz-30 kHz BW) ≤0.0005 UI ≤-30 dB below jitter signal  STICS AES/EBU (per AES 3-1992) 28.8 kHz-52.8 kHz AES/EBU ±0.0025% [±25 PPM]  ICS AES/EBU (per AES 3-1992); SPDIF-EIAJ; Optical 28.8 kHz-52.8 kHz AES/EBU Add 57.6 kHz-105.6 kHz 12 to 24 bits
Residual Jitter RMS response Peak response Spurious Jitter Products Jitter & Ref Delay Off Jitter On REFERENCE INPUT CHARACTER! Input Formats Input Sample Rates Lock Range DIGITAL ANALYZER DIGITAL INPUT CHARACTERIST. Input Formats Sample Rates With 96k Option	10 Hz to 38.8 kHz 0-1.28 UI (pk), in steps of 0.005 UI or better 1.3-12.75 UI, in steps of 0.05 UI or better (total generator/analyzer) peak calibrated ≤0.005 UI (700 Hz-30 kHz BW) ≤0.015 UI (700 Hz-30 kHz BW) ≤0.0005 UI ≤-30 dB below jitter signal  STICS AES/EBU (per AES 3-1992) 28.8 kHz-52.8 kHz AES/EBU ±0.0025% [±25 PPM]  ICS AES/EBU (per AES 3-1992); SPDIF-EIAJ; Optical 28.8 kHz-52.8 kHz AES/EBU Add 57.6 kHz-105.6 kHz 12 to 24 bits
Residual Jitter RMS response Peak response Peak response Spurious Jitter Products Jitter & Ref Delay Off Jitter On REFERENCE INPUT CHARACTER! Input Formats Input Sample Rates Lock Range DIGITAL ANALYZER DIGITAL INPUT CHARACTERIST. Input Formats Sample Rates With 96k Option Word Width EMBEDDED AUDIO MEASUREME Wideband Level/Amplitude Range	10 Hz to 38.8 kHz 0-1.28 UI (pk), in steps of 0.005 UI or better 1.3-12.75 UI, in steps of 0.05 UI or better (total generator/analyzer) peak calibrated ≤0.005 UI (700 Hz-30 kHz BW) ≤0.015 UI (700 Hz-30 kHz BW) ≤0.005 UI ≤-30 dB below jitter signal  STICS  AES/EBU (per AES 3-1992) 28.8 kHz-52.8 kHz AES/EBU ±0.0025% [±25 PPM]  ICS  AES/EBU (per AES 3-1992); SPDIF-EIAJ; Optical 28.8 kHz-52.8 kHz AES/EBU Add 57.6 kHz-105.6 kHz 12 to 24 bits  NTS  0 dBFS to -140 dBFS
Residual Jitter RMS response Peak response Peak response Spurious Jitter Products Jitter & Ref Delay Off Jitter On REFERENCE INPUT CHARACTER! Input Formats Input Sample Rates Lock Range DIGITAL ANALYZER DIGITAL INPUT CHARACTERIST. Input Formats Sample Rates With 96k Option Word Width EMBEDDED AUDIO MEASUREME Wideband Level/Amplitude Range Frequency Range Accuracy	10 Hz to 38.8 kHz 0-1.28 UI (pk), in steps of 0.005 UI or better 1.3-12.75 UI, in steps of 0.05 UI or better (total generator/analyzer) peak calibrated ≤0.005 UI (700 Hz-30 kHz BW) ≤0.015 UI (700 Hz-30 kHz BW) ≤3.0 dB below jitter signal  STICS  AES/EBU (per AES 3-1992) 28.8 kHz-52.8 kHz AES/EBU ±0.0025% [±25 PPM]  ICS  AES/EBU (per AES 3-1992); SPDIF-EIAJ; Optical 28.8 kHz-52.8 kHz AES/EBU Add 57.6 kHz-105.6 kHz 12 to 24 bits  NTS  O dBFS to -140 dBFS <10 Hz-22.0 kHz at 48 ks/sec ±0.01 dB, ±90 dBFS
Residual Jitter RMS response Peak response Peak response Spurious Jitter Products Jitter & Ref Delay Off Jitter On REFERENCE INPUT CHARACTER! Input Formats Input Sample Rates Lock Range DIGITAL ANALYZER DIGITAL INPUT CHARACTERIST. Input Formats Sample Rates With 96k Option Word Width EMBEDDED AUDIO MEASUREME Wideband Level/Amplitude Range Frequency Range Accuracy Flatness High pass Filters	10 Hz to 38.8 kHz 0-1.28 UI (pk), in steps of 0.005 UI or better 1.3-12.75 UI, in steps of 0.05 UI or better (total generator/analyzer) peak calibrated ≤0.005 UI (700 Hz-30 kHz BW) ≤0.015 UI (700 Hz-30 kHz BW) ≤3.005 UI ≤-30 dB below jitter signal  STICS  AES/EBU (per AES 3-1992) 28.8 kHz-52.8 kHz AES/EBU ±0.0025% [±25 PPM]  ICS  AES/EBU (per AES 3-1992); SPDIF-EIAJ; Optical 28.8 kHz-52.8 kHz AES/EBU 40.57 kHz-105.6 kHz 12 to 24 bits  NTS  0 dBFS to -140 dBFS <10 Hz-22.0 kHz at 48 ks/sec ±0.01 dB, ±-90 dBFS <10.01 dB, ±-90 dBFS <10.01 dB, ±-90 dBFS ±0.01 dB, ±-90 dBFS
Residual Jitter RMS response Peak response Peak response Spurious Jitter Products Jitter & Ref Delay Off Jitter On REFERENCE INPUT CHARACTER! Input Formats Input Sample Rates Lock Range  DIGITAL ANALYZER DIGITAL INPUT CHARACTERIST Input Formats Sample Rates With 96k Option Word Width EMBEDDED AUDIO MEASUREME Wideband Level/Amplitude Range Frequency Range Accuracy Flatness High pass Filters Low pass Filters	10 Hz to 38.8 kHz 0-1.28 UI (pk), in steps of 0.005 UI or better 1.3-12.75 UI, in steps of 0.05 UI or better (total generator/analyzer) peak calibrated ≤0.005 UI (700 Hz-30 kHz BW) ≤0.015 UI (700 Hz-30 kHz BW) ≤3.005 UI ≤-30 dB below jitter signal  STICS  AES/EBU (per AES 3-1992) 28.8 kHz-52.8 kHz AES/EBU ±0.0025% [±25 PPM]  ICS  AES/EBU (per AES 3-1992); SPDIF-EIAJ; Optical 28.8 kHz-52.8 kHz AES/EBU Add 57.6 kHz-105.6 kHz 12 to 24 bits  NTS  0 dBFS to -140 dBFS <10 Hz-22.0 kHz at 48 ks/sec ±0.01 dB, ±-90 dBFS <10.01 dB, ±-90 dBFS <10.01 dB, ±-90 dBFS ±0.01 dB, ±-90 dBFS
Residual Jitter RMS response Peak response Peak response Spurious Jitter Products Jitter & Rf Delay Off Jitter Off REFERENCE INPUT CHARACTER! Input Formats Input Sample Rates Lock Range  DIGITAL ANALYZER DIGITAL INPUT CHARACTERIST. Input Formats Sample Rates With 96k Option Word Width EMBEDDED AUDIO MEASUREME Wideband Level/Amplitude Range Frequency Range Accuracy Flatness High pass Filters Low pass Filters Weighting Filters	10 Hz to 38.8 kHz 0-1.28 UI (pk), in steps of 0.005 UI or better 1.3-12.75 UI, in steps of 0.05 UI or better (total generator/analyzer) peak calibrated ≤0.005 UI (700 Hz-30 kHz BW) ≤0.015 UI (700 Hz-30 kHz BW) ≤0.005 UI ≤-30 dB below jitter signal  STICS  AES/EBU (per AES 3-1992) 28.8 kHz-52.8 kHz AES/EBU ±0.0025% [±25 PPM]  CCS  AES/EBU (per AES 3-1992); SPDIF-EIAJ; Optical 28.8 kHz-52.8 kHz AES/EBU Add 57.6 kHz-105.6 kHz 12 to 24 bits  NTS  0 dBFS to -140 dBFS <10 Hz-22.0 kHz at 48 ks/sec ±0.01 dB, ±90 dBFS ±0.01 dB, 15 Hz-22 kHz 22 Hz, 400 Hz, 2-pole Butterworth 15 kHz, 20 kHz 6-pole elliptic low-pass ANSI-IEC "A" weighting; CCIR QPK; CCIR RMS
Residual Jitter RMS response Peak response Peak response Spurious Jitter Products Jitter & Ref Delay Off Jitter On REFERENCE INPUT CHARACTER! Input Formats Input Sample Rates Lock Range  DIGITAL ANALYZER DIGITAL INPUT CHARACTERIST Input Formats Sample Rates With 96k Option Word Width EMBEDDED AUDIO MEASUREME Wideband Level/Amplitude Range Frequency Range Accuracy Flatness High pass Filters Low pass Filters	10 Hz to 38.8 kHz 0-1.28 UI (pk), in steps of 0.005 UI or better 1.3-12.75 UI, in steps of 0.05 UI or better (total generator/analyzer) peak calibrated ≤0.005 UI (700 Hz-30 kHz BW) ≤0.015 UI (700 Hz-30 kHz BW) ≤0.0005 UI ≤-30 dB below jitter signal  STICS  AES/EBU (per AES 3-1992) 28.8 kHz-52.8 kHz AES/EBU ±0.0025% [±25 PPM]  ICS  AES/EBU (per AES 3-1992); SPDIF-EIAJ; Optical 28.8 kHz-52.8 kHz AES/EBU 40.0025% [±25 PPM]  ICS  AES/EBU (per AES 3-1992); SPDIF-EIAJ; Optical 28.8 kHz-52.8 kHz AES/EBU Add 57.6 kHz-105.6 kHz 12 to 24 bits  NTS  OdBFS to -140 dBFS <10 Hz-22.0 kHz at 48 ks/sec ±0.01 dB, ±90 dBFS ±0.01 dB

0.04% to 40% of sample rate (10 Hz-19.2 kHz at 48.0 ks/sec) 10-pole, Q=19 (BW = 5.3% of f <sub>0</sub> )
F200/ 4 22 (211 - 212 to 01 10)
0.02% to 45% of sample rate
(10 Hz-22.0 kHz at 48.0 ks/sec
≤-136 dBFS
22 Hz, 400 Hz 2-pole Butterworth 15 kHz, 20 kHz 6-pole elliptic
low-pass
ANSI-IEC "A" weighting; CCIR QPK; CCIR RMS
-140 dBFS unweighted; -142 dBFS
A-weighted
th option "P1-IMD"
40-250 Hz and 3 kHz-20 kHz in 1:1 to 4:1 ratio
Amplitude modulation products of
the HF tone.
<0.0001%-10% ±1 dB per SMPTE RP-120-1983,
DIN 45403
≤0.0001% [-120 dB], 60 + 7 kHz o 250 + 8 kHz
5 Hz to 47% of sample rate
±180, +90/-270, or -90/+270 deg
±2.0 deg (20 Hz-20 kHz)
0.1 deg
Compatible with random mode of or System Products' BITTEST
JREMENTS
me Displays
±0.002% [±20 PPM] internal ref,±0.0001% [*1 PPM] external ref
Measures status propagation from
the AES/EBU output to the input.
Range is 0–192 (frames), resolution ±60 ns.
200 mV to 10 24 Vpp
200 mV to 10.24 Vpp, ±(5% + 50 mV)
100 mV to 2.56 Vpp, ±(5% + 12 mV
(peak-peak sinewave calibrated) 0- UI,
±1.5 dB, 100 Hz-22 kHz (50 Hz HP
selection, RMS detection, 48 kHz
sample rate) (analyzer only) (700 Hz-30 kHz
(analyzer only) (700 Hz–30 kHz BW)≤0.01 UI RMS; ≤0.03 UI Peak
≤0.002 UI (1.2 kHz) or 0 dB below jitter signal
English language decoded
(Professional/Consumer)
Displayed for selected channel Displayed for total signal (both
channels combined)
Digital Comp Output A 1
Digital Sync Output; Analyzer Input
Typically 1 Watt
\L
100/120/230/240 Vac (-10%/+6%) 50-60 Hz, 50 VA max
0° C to +40° C Operating; -20° C to
+60° C Storage 90% RH to at least +40° C
(non-condensing)
Lomplies with 89/336/EEC, CISPR 2
(class B) and FCC 15 cubnart 1 (class
(class B), and FCC 15 subpart J (class 16.5 x 6.0 x 13.6 inches [41.9 x 15
16.5 x 6.0 x 13.6 inches [41.9 x 15 x 34.5 cm]
Complies with 89/336/EEC, CISPR 2 (class B), and FCC 15 subpart J (class 16.5 x 6.0 x 13.6 inches [41.9 x 15 x 34.5 cm] Approximately 20 lbs [9.1 kg] Complies with 73/23/EEC, 93/68/EEC, EN61010, and IEC 1010



Ordering Information	
P1PA	Portable One <i>Plus</i> Access Audio Test System with GPIB interface
P1DD	Portable One Dual Domain (digital and analog) Audio Test System with GPIB interface
Options and Acce	essories for Portable One Instruments
P1-IMD	SMPTE/DIN intermodulation distortion measurement and generation (analog and digital)
P-CAS	Protective soft carrying case with shoulder strap and internal/external pockets
RAK-P1	Rack mount shelf for Portable One <i>Plus</i> Access or Portable One Dual Domain
96K-P1DD	96kHz Digital Audio sampling rate option for Portable One Dual Domain(at time of original instrument order
MAN-P1PA	Additional Portable One <i>Plus</i> Access operator's manua (one included with instrument)
MAN-P1DD	Additional Portable One Dual Domain operator's manual (one included with instrument)
MAN-P488	GPIB manual for Portable One <i>Plus</i> Access or Portable One Dual Domain
SVC-P1	Service manual for Portable One <i>Plus</i> Access or Portable One Dual Domain
SC-P1	1 Year Service Contract
CAB-XMF	Set of four XLR male to XLR female cables
CAB-XBR	Set of four XLR male/female to RCA/BNC cables
CAB-AES	Set of two AES/EBU cables, 1 meter
CAB-AES2	Set of two AES/EBU cables, 2 meters
CAB-AES4	Set of two AES/EBU cables, 4 meters

Soft carrying case option Padded interior protects Portable One. Extra pocket for documentation, and cables.

### BUYING A PORTABLE ANALYZER FOR ANALOG AND DIGITAL AUDIO:

What to look for when evaluating competitive instruments

**Digital Architecture and Features:** Not all analyzers that accept a digital input signal are actually digital analyzers. Does the instrument have a real (DSP-implemented) digital domain analyzer, or just a D/A converter from the digital input connector to an analog hardware analyzer? This latter approach in a competitive unit yields distortion performance in the 12-14 bit range (-70 to -85 dB THD+N, for example).There's just not that much 12-bit digital audio around to measure anymore. Portable One Dual Domain's digital analyzer guarantees -130 dB residual distortion (nearly 22 bit performance), far in excess of the -105 to -108 dB actual linearity of today's best A/D converters.

Analog Performance: Does the instrument have an analog hardware generator and an analog hardware analyzer? Some competitive units (at twice the price of Portable One Dual Domain) use DSP techniques for all

generation and analysis, so analog signals pass through converters inside the instrument. The result is THD+N as high as -79 dB, flatness as poor as -0.2 dB — inadequate for most modern audio devices.

Interface Testing: Does the instrument have independent analog, digital, and jitter generators? If it can only provide analog or digital output at any one time, you can't test a house-synchronized A/D converter for jitter rejection. Without independent, flexible digital audio and jitter generators, you can't measure jitter sensitivity of a D/A converter at various audio and jitter frequency combinations.

**True Dual Domain:** True Dual Domain hardware by definition guarantees a full range of analysis capabilities in both analog and digital domains. Everyone measures level and some measure THD+N (although implemented with extremely limited performance, as noted above). Be sure that other useful measurements such as IMD (Intermodulation Distortion), Phase, and Crosstalk are available for both analog and digital signals, not just analog.



Testing for Optimal Results

Available from:

Thurlby Thandar Instruments Ltd. Glebe Road, Huntingdon, Cambs. PE29 7DR U.K. **Tel: 01480 412451** e-mail: sales@tti-test.com **Web: www.tti-test.com** or www.tti.co.uk